

SU6/SUC6 Series EMI/EMS Test resultsApproved : *Tetsuo Sugimori*Prepared : *Yuji Hirose*

No.	Test item	Conditions	Conditions of Acceptability	Result
1	Line conduction	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Meets the undermentioned FCC Part15 classA , VCCI classA CISPR22 classA , EN55022-A	OK
2	Radiated emission	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Meets the undermentioned FCC Part15 classA , VCCI classA CISPR22 classA , EN55022-A	OK
3	Static electricity immunity test (EN61000-4-2)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Contact discharge voltage 8[kV] (EN61000-4-2 Level 4) (5) Testing circuitry Fig.2	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
4	Radiated, radio-frequency, electromagnetic field immunity test (EN61000-4-3)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4)Testing field strength 10[V/m] (EN61000-4-3 Level 3) (5) Testing circuitry Fig.1	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
5	Electrical fast transient/ burst immunity test (EN61000-4-4)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Test peak voltage 4[kV] (IEC61000-4-4 Level 4) (5) Testing circuitry Fig.2	(1)No protection circuit failure. (2)No output voltage drop with control circuit failure. (3)No any other function failure	OK
6	Surge immunity test (EN61000-4-5)	(1) Rated input (2) Rated load (3) Ambient temp. 25±10°C (4) Test voltage Line to line 2[kV] (Level 4) (5) Testing circuitry Fig.3	(1)The power supply is not sto (2)Circuit does not malfunction. (3)No abnormality of the insulation destruction etc. (4)Parts are no damaged.	OK

○ Testing circuitry

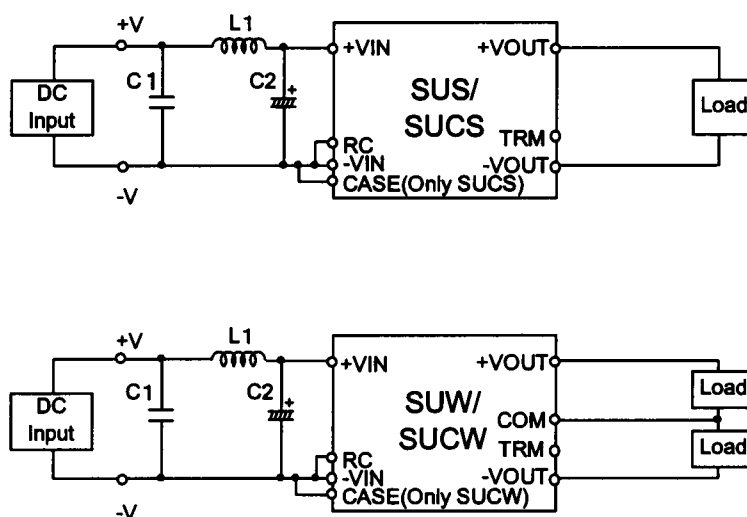


Fig.1 Testing circuitry

SU□/SUC□605

L1 : 0.5 μ H	CY3H-R50	(KORIN ELECTRONICS)
C1 : 25V 2.2 μ F	C3216JB1E225K	(TDK)
C2 : 16V 470 μ F	LXZ16VB470(M)	(NIPPON CHEMI-COM)

SU□/SUC□612

L1 : 1 μ H	CY3H-1R0	(KORIN ELECTRONICS)
C1 : 25V 1 μ F	C3216JB1E105K	(TDK)
C2 : 25V 220 μ F	LXZ25VB220(M)	(NIPPON CHEMI-COM)

SU□/SUC□624

L1 : 2.2 μ H	CY3H-2R2	(KORIN ELECTRONICS)
C1 : 50V 2.2 μ F	C3225X5R1H225M	(TDK)
C2 : 50V 100 μ F	UPM1H101M	(NICHICON)

SU□/SUC□648

L1 : 6.8 μ H	CY3H-6R8	(KORIN ELECTRONICS)
C1 : 100V 1 μ F	C3225JB2A105M	(TDK)
C2 : 100V 47 μ F	UPW2A470M	(NICHICON)

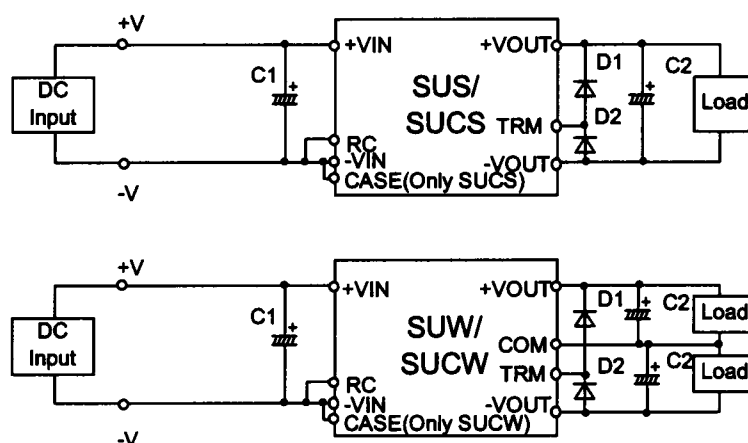


Fig.2 Testing circuitry

C1 :	SU□/SUC□605	16V	470 μ F	LXZ16VB470(M)	(NIPPON CHEMI-COM)
	SU□/SUC□612	25V	220 μ F	LXZ25VB220(M)	(NIPPON CHEMI-COM)
	SU□/SUC□624	50V	100 μ F	UPM1H101M	(NICHICON)
	SU□/SUC□648	100V	47 μ F	UPW2A470M	(NICHICON)

C2 :	SU□/SUC□6□□3R3	25V	220 μ F	LXZ25VB220(M)	(NIPPON CHEMI-COM)
	SU□/SUC□6□□05	25V	220 μ F	LXZ25VB220(M)	(NIPPON CHEMI-COM)
	SU□/SUC□6□□12	25V	100 μ F	UPM1E101M	(NICHICON)
	SU□/SUC□6□□15	25V	100 μ F	UPM1E101M	(NICHICON)

D1 :	SU□/SUC□6	100V	1A	D5566B	(TOSHIBA)
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D2 :	SU□/SUC□6	100V	1A	D5566B	(TOSHIBA)
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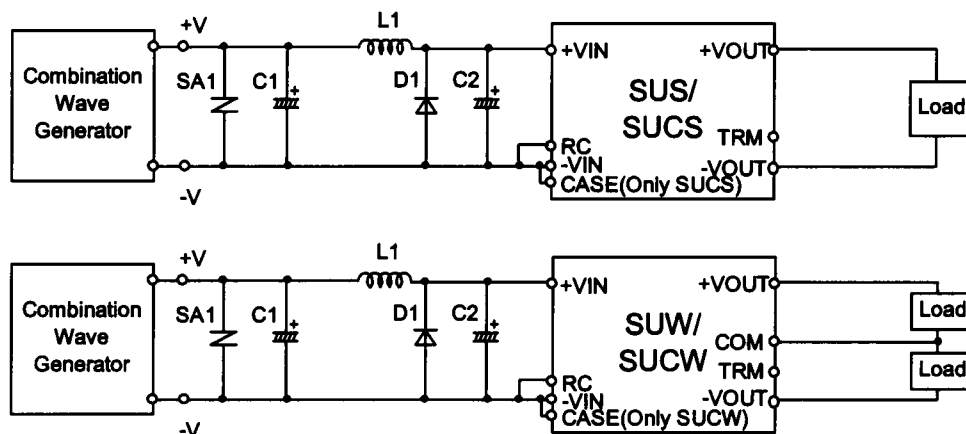


Fig.3 Surge immunity testing circuitry

SU□/SUC□605

SA1 : 18V		ERZV10D180	(MATSUSHITA ELECTRONIC)
L1 : 3.3 μ H		CY3H-3R3	(KORIN ELECTRONICS)
D1 : 200V 3A		ERD32-02	(FUJI ELECTRIC)
C1 : 16V 470 μ F		LXZ16VB470(M)	(NIPPON CHEMI-COM)
C2 : 16V 470 μ F		LXZ16VB470(M)	(NIPPON CHEMI-COM)

SU□/SUC□612

SA1 : 27V		ERZV10D270	(MATSUSHITA ELECTRONIC)
L1 : 1 μ H		CY3H-1R0	(KORIN ELECTRONICS)
D1 : 200V 3A		ERD32-02	(FUJI ELECTRIC)
C1 : 25V 220 μ F		LXZ25VB220(M)	(NIPPON CHEMI-COM)
C2 : 25V 220 μ F		LXZ25VB220(M)	(NIPPON CHEMI-COM)

SU□/SUC□624

SA1 : 47V		ERZV10D470	(MATSUSHITA ELECTRONIC)
L1 : 2.2 μ H		CY3H-2R2	(KORIN ELECTRONICS)
D1 : 200V 3A		ERD32-02	(FUJI ELECTRIC)
C1 : 50V 100 μ F		UPM1H101M	(NICHICON)
C2 : 50V 100 μ F		UPM1H101M	(NICHICON)

SU□/SUC□648

SA1 : 100V		ERZV10D101	(MATSUSHITA ELECTRONIC)
L1 : 6.8 μ H		CY3H-6R8	(KORIN ELECTRONICS)
D1 : 200V 3A		ERD32-02	(FUJI ELECTRIC)
C1 : 100V 47 μ F		UPW2A470M	(NICHICON)
C2 : 100V 47 μ F		UPW2A470M	(NICHICON)